



AON7408 30V N-Channel MOSFET

General Description

The AON7408 uses advanced trench technology and design to provide excellent $R_{\text{DS(ON)}}$ with low gate charge. This device is suitable for use in general purpose applications.

Features

 $V_{DS}(V) = 30V$

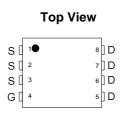
 $I_D = 23A$ $(V_{GS} = 10V)$

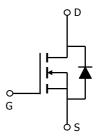
 $R_{DS(ON)}$ < 22m Ω (V_{GS} = 10V)

 $R_{DS(ON)} < 34m\Omega$ ($V_{GS} = 4.5V$)

100% UIS Tested!







Absolute Maximum Ratings T _A =25℃ unless otherwise noted					
Parameter	Symbol				
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Parameter		Symbol	Maximum	Units
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain	T _C =25℃		23	
Current ^B	T _C =100℃	I_D	15	
Pulsed Drain Current ^C		I_{DM}	50	A
Continuous Drain	T _A =25℃		9.6	
Current ^A	T _A =70℃	I _{DSM}	7.7	
	T _C =25℃	В	20	
Power Dissipation ^B	T _C =100℃	-P _D	8.3	W
	T _A =25℃	В	3.1	VV
Power Dissipation ^A	T _A =70℃	P _{DSM}	2]
Junction and Storage	Temperature Range	T_J, T_{STG}	-55 to 150	ς.

Thermal Characteristics					
Parameter		Symbol	Тур	Max	Units
Maximum Junction-to-Ambient A	t ≤ 10s	В	25	40	°C/W
Maximum Junction-to-Ambient A	Steady-State	$-$ R _{θJA}	62	75	°C/W
Maximum Junction-to-Case B	Steady-State	$R_{\theta JC}$	5	6	.c\M

Electrical Characteristics (T_J=25℃ unless otherwise noted)

Symbol	Parameter	Conditions	Conditions		Тур	Max	Units
STATIC F	PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	$I_D = 250 \mu A, V_{GS} = 0 V$				V
I _{DSS} Zero Gate Voltage Drain Current	V_{DS} =30V, V_{GS} =0V				1	μA	
DSS	I _{DSS} Zero Gate Voltage Drain Current		T _J =55℃			5	μΑ
I _{GSS}	Gate-Body leakage current	V_{DS} =0V, V_{GS} = ±20V				±100	nA
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$		1	1.6	3	V
I _{D(ON)}	On state drain current	V_{GS} =10V, V_{DS} =5V		50			Α
		V_{GS} =10V, I_D =9A			18	22	
R _{DS(ON)}	R _{DS(ON)} Static Drain-Source On-Resistance		T _J =125℃		26	32	$m\Omega$
	V_{GS} =4.5V, I_D =5A	V _{GS} =4.5V, I _D =5A		27	34		
g FS	Forward Transconductance	$V_{DS}=5V$, $I_{D}=9A$	V_{DS} =5V, I_{D} =9A		24		S
V_{SD}	Diode Forward Voltage	I _S =1A,V _{GS} =0V	I _S =1A,V _{GS} =0V		0.75	1	V
I _S	Maximum Body-Diode Continuous Cur	aximum Body-Diode Continuous Current				1.7	Α
DYNAMIC	CPARAMETERS						
C _{iss}	Input Capacitance				621	820	pF
C _{oss}	Output Capacitance	V_{GS} =0V, V_{DS} =15V, f=1MHz V_{GS} =0V, V_{DS} =0V, f=1MHz			118		pF
C_{rss}	Reverse Transfer Capacitance				85		pF
R_g	Gate resistance				0.8	1.5	Ω
SWITCHI	NG PARAMETERS						
Q_g	Total Gate Charge				6	8	nC
Q_{gs}	Gate Source Charge	V_{GS} =4.5V, V_{DS} =15V,	I _D =9A		2.1		nC
Q_{gd}	Gate Drain Charge		1		3		nC
t _{D(on)}	Turn-On DelayTime				4.5		ns
t _r	Turn-On Rise Time	V _{GS} =10V, V _{DS} =15V,	V_{GS} =10V, V_{DS} =15V, R_L =1.7 Ω ,		3.1		ns
t _{D(off)}	Turn-Off DelayTime	$R_{GEN}=3\Omega$			15.1		ns
t _f	Turn-Off Fall Time				2.7		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =9A, dI/dt=100A/μs			15.5	20	ns
Q _{rr}	Body Diode Reverse Recovery Charge	e I _F =9A, dI/dt=100A/μs	I _F =9A, dI/dt=100A/μs		7.1		nC
	e of Rola is measured with the device in a still air		The newer disci	nation D	and au	rrant ratina	

A: The value of $R_{\theta JA}$ is measured with the device in a still air environment with T_A =25°C. The power dissipation P_{DSM} and current rating I_{DSM} are based on $T_{J(MAX)}$ =150°C, using t \leq 10s junction-to-ambient thermal resistance.

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B. The power dissipation P_D is based on $T_{J(MAX)}$ =150°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$ =150°C.

D. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to case $R_{\theta JC}$ and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}$ =150°C. The SOA curve provides a single pulse ratin g.

G. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25℃.

H. The maximum current rating is limited by bond-wires.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

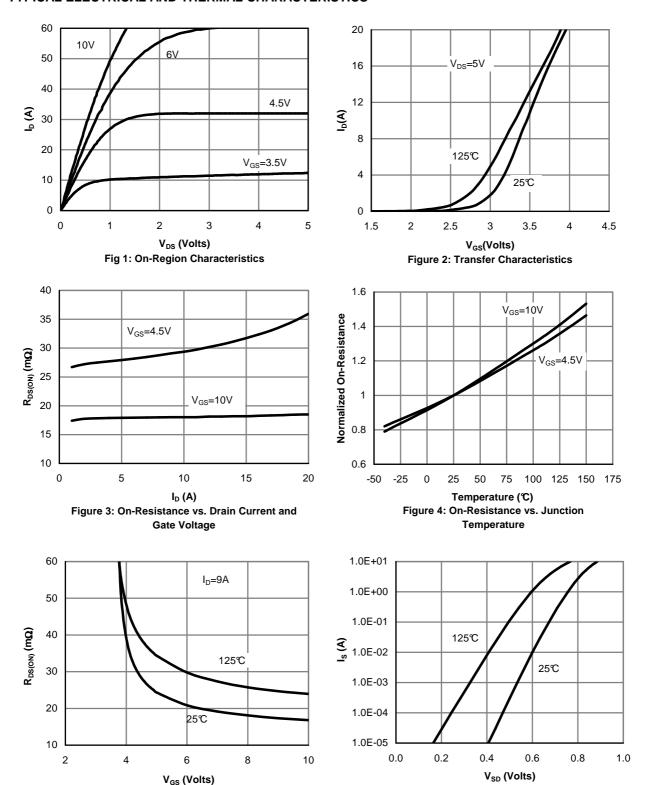


Figure 5: On-Resistance vs. Gate-Source Voltage

Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

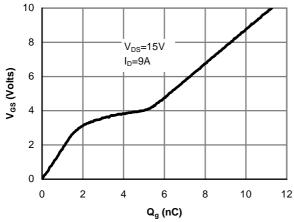


Figure 7: Gate-Charge Characteristics

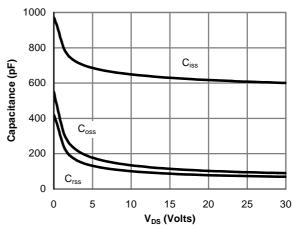


Figure 8: Capacitance Characteristics

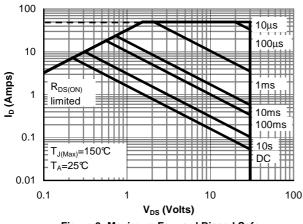


Figure 9: Maximum Forward Biased Safe Operating Area (Note H)

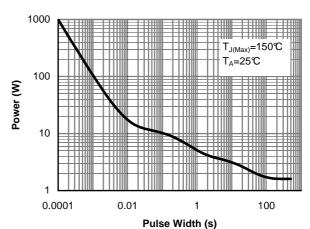


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note H)

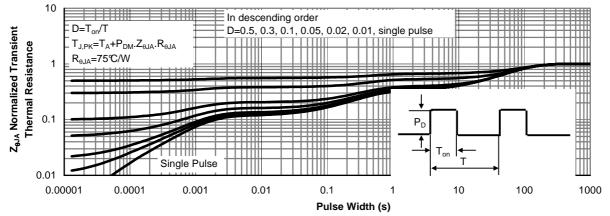


Figure 11: Normalized Maximum Transient Thermal Impedance (Note H)